

Test Report No. <i>Prüfbericht-Nr.:</i>	US24AI4K 001	Order No. <i>Auftrags-Nr.:</i>	P01387797 234057357	Page 1 of 81 Seite 1 von 81
Client Reference No.: <i>Kunden-Referenz-Nr.:</i>	2239931	Order date: <i>Auftragsdatum:</i>	02/15/2024	
Client: <i>Auftraggeber:</i>	Tokenize, Inc. 4545 East River Road W. Henrietta, NY 14586			
Identification/ Type <i>No.:</i> <i>Bezeichnung / Typ-Nr</i>	TokenRing V3, Token Biostick			
Order content: <i>Auftrags-Inhalt:</i>	FCC 15.225 and RSS 210 RFID Compliance Evaluation			
Test specification: <i>Prüfgrundlage</i>	CFR Title 47 Subchapter A §Part 15.225 ISED RSS-210 Issue 10			
Date of sample receipt: <i>Wareneingangsdatum:</i>	TR3: 6/4/2024 TBK: 8/15/2025			
Test sample No: <i>Prüfmuster-Nr.:</i>	TR3: Test Sample Number: A003741573 Serial Number: 240802ZD2406 TBK: Test Sample Number: A004076538 Serial Number: K02BA15C00088			
Testing period: <i>Prüfzeitraum</i>	TR3: 6/4/2024 - 6/11/2024 & 8/26/2025 TBK: 8/15/2025 – 8/26/2025			
Place of testing: <i>Ort der Prüfung:</i>	TUV Rheinland of North America Inc. 5015 Brandin Ct Fremont CA 94538 USA			
Testing laboratory: <i>Prüflaboratorium</i>	TUV Rheinland of North America, Inc.			
Test result*: <i>Prüfergebnis*:</i>	Pass			
compiled by: <i>geprüft von:</i> Date: 8/26/2025 <i>Datum:</i>	Nathaniel Beyer 	Authorized by: <i>genehmigt von:</i> Issue Date: 8/26/2025 <i>Ausstellungsdatum:</i>	Dieter Baldamus Paasche 	
Position / Stellung:	Test Engineer	Position / Stellung:	Expert	
Others / Sonstiges:				
Condition of the test item at delivery: <i>Zustand des Prüfgegenstandes bei Anlieferung:</i>				
* Legend:	P(ass) = passed a.m. test specification(s)	F(ail) = failed a.m. test specification(s)	N/A = not applicable	N/T = not tested
* Legende:	P(ass) = entspricht o.g. Prüfgrundlage(n)	F(ail) = entspricht nicht o.g. Prüfgrundlage(n)	N/A = nicht anwendbar	N/T = nicht getestet
This test report only relates to the a. m. test sample. Without permission of the test center this test report is not permitted to be duplicated in extracts. This test report does not entitle to carry any test mark. <i>Dieser Prüfbericht bezieht sich nur auf das o.g. Prüfmuster und darf ohne Genehmigung der Prüfstelle nicht auszugsweise vervielfältigt werden. Dieser Bericht berechtigt nicht zur Verwendung eines Prüfzeichens.</i>				



Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 2 of 81
Seite 2 von 81

Remarks
Anmerkungen

1	The equipment used during the specified testing period was calibrated according to our test laboratory calibration program. The equipment fulfils the requirements included in the relevant standards. The traceability of the test equipment used is ensured by compliance with the regulations of our management system. Detailed information regarding test conditions, equipment and measurement uncertainty is available in the test laboratory and could be provided on request. <i>Alle eingesetzten Prüfmittel waren zum angegebenen Prüfzeitraum gemäß eines festgelegten Kalibrierungsprogramms unseres Prüfhauses kalibriert. Sie entsprechen den in den Prüfprogrammen hinterlegten Anforderungen. Die Rückverfolgbarkeit der eingesetzten Prüfmittel ist durch die Einhaltung der Regelungen unseres Managementsystems gegeben.</i> <i>Detaillierte Informationen bezüglich Prüfkonditionen, Prüfequipment und Messunsicherheiten sind im Prüflabor vorhanden und können auf Wunsch bereitgestellt werden.</i>
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3	Test clauses with remark of * are subcontracted to qualified subcontractors and described under the respective test clause in the report. Deviations of testing specification(s) or customer requirements are listed in specific test clause in the report. <i>Prüfklausel mit der Note * wurden an qualifizierte Unterauftragnehmer vergeben und sind unter der jeweiligen Prüfklausel des Berichts beschrieben.</i> <i>Abweichungen von Prüfspezifikation(en) oder Kundenanforderungen sind in der jeweiligen Prüfklausel im Bericht aufgeführt.</i>
4	Electromagnetic Compatibility Test Report. The above product was found to be Compliant to the above test standard(s).

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 3 of 81
Seite 3 von 81

Product description
Produktbeschreibung

1	Product details: <i>Produktdetails:</i>	TokenRing V3, Token Biostick
2	Dimensions / Weight: <i>Maße / Gewicht:</i>	30mm x 30mm x 15mm
3	Operating elements: <i>Bedienelemente:</i>	5V DC
4	Equipment / Accessories: <i>Ausstattung / Zubehör:</i>	N/A
5	Used materials: <i>Verwendete Materialien:</i>	N/A
6	Other: <i>Sonstiges:</i>	Test sample(s), as well sample information, description, product details and intended usage was provided by customer.
7	Test sample obtaining: <i>Prüfmusterbereitstellung:</i>	☒ Sending by customer ☐ Sampling by TÜV Rheinland Group ☐ others:

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 5 of 81
Seite 5 von 81

1	Executive Summary	8
1.1	Scope	8
1.2	Purpose	8
1.3	Summary of Test Results	8
1.4	Special Accessories	8
1.5	Equipment Modifications	9
2	Laboratory Information	9
2.1	Accreditations & Endorsements	9
2.1.1	US Federal Communications Commission, US1131	9
2.1.2	NIST / A2LA, Testing Cert #3331.02	9
2.1.3	Canada – Innovation, Science and Economic Development (ISED), 2932D	9
2.1.4	Japan – VCCI	9
2.1.5	Acceptance by Mutual Recognition Arrangement	10
2.2	Test Facilities	10
2.2.1	Emission Test Facility	10
2.3	Measurement Uncertainty	10
2.3.1	Sample Calculation – radiated & conducted emissions	11
2.3.2	Measurement Uncertainty	11
2.3.3	Measurement Uncertainty Immunity	12
2.4	Calibration Traceability	12
3	EMC Test Plan	13
3.1	Introduction	13
3.2	Customer	13
3.3	Equipment Under Test (EUT)	14
4	Product Information	16
4.1	Product Description	16
4.2	Equipment Configuration	16
4.3	Operating Mode	16
4.4	Unique Antenna Connector	16
4.4.1	Results	16
5	Measurement Results	17
5.1	Duty Cycle	18
5.2	Results	18
5.3	Fundamental Field Strength	19
5.3.1	Test Methodology	19
5.3.2	Results	19
5.4	Occupied Bandwidth	20
5.4.1	Test Methodology	20
5.4.2	Results	20

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 6 of 81
Seite 6 von 81

5.5	Carrier Frequency Stability	21
5.5.1	Test Methodology	21
5.5.2	Results	21
5.6	Radiated Spurious Emissions	23
5.6.1	Test Methodology	23
5.6.2	Transmitter Spurious Emission Limit	24
5.6.3	Test Results	25
5.6.4	Emission Mask	25
5.6.5	Spurious Emissions	30
5.7	AC Mains Conducted Emissions	36
5.7.1	Test Methodology	36
5.7.2	Conducted Emission Limits	36
5.7.3	Deviations	36
5.7.4	Test Results	36
6	Test Equipment List	41
6.1	Equipment List	41
6.2	Testing Software	42
7	Appendix: Test Setup Photos	44
7.1	Radiated Emissions 9 kHz to 30 MHz	44
7.2	Radiated Emissions 30 to 1000 MHz	47
7.3	Frequency Stability	48
7.4	Conducted Emissions	50
7.5	Test Setup Photos for Model: TBK	51
8	Appendix: Equipment Under Test (EUT) Photos	56
9	Appendix: Equipment Under Test (EUT) Internal Photos	59
10	Appendix: Additional Testing for Model TBK	66
10.1	Measurement Results	66
10.2	Radiated Spurious Emissions	66
10.2.1	Test Methodology	67
10.2.2	Transmitter Spurious Emission Limit	68
10.2.3	Test Results	69
10.2.4	Spurious Emissions	69
10.3	AC Mains Conducted Emissions	77
10.3.1	Test Methodology	77
10.3.2	Conducted Emission Limits	77
10.3.3	Deviations	77
10.3.4	Test Results	77

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 7 of 81
Seite 7 von 81

Table 1: Summary of Test Results	8
Table 2: Customer Information.....	13
Table 3: Technical Contact Information	13
Table 4: EUT Specifications.....	14
Table 5: EUT Test Samples	15
Table 6: Channerl Power Setting/Specifcation.....	15
Table 7: General Product Infromation	15
Table 8: Electrical Power Type.....	15
Table 9: EUT Interface/Port Specifications	15
Table 10: Duty Cycle	18
Table 11: Fundamental Field Strength.....	19
Table 12: Fundamental Field Strength.....	20
Table 13: Frequency Stability Over Temp (%)	21
Table 14: Frequency Stability Over Temp (PPM)	21
Table 15: Frequency Stability Over Voltage (%)	22
Table 16: Frequency Stability Over Voltage (PPM)	22
Table 17: Emissions Mask – X-Axis.....	25
Table 18: Emissions Mask – Y-Axis.....	26
Table 19: Emissions Mask – Z-Axis.....	27
Table 20: 9 kHz – 30 MHz Spurious Emissions on X-Axis.....	30
Table 21: 9 kHz – 30 MHz Spurious Emissions on Y-Axis.....	31
Table 22: 9 kHz – 30 MHz Spurious Emissions on Z-Axis.....	32
Table 23: 30 – 1000 MHz Spurious Emissions	33
Table 24: AC Conducted Emission limits.....	36
Table 25: Conducted Emission – 13.56 MHz, Line.....	37
Table 26: Conducted Emissions – 13.56 MHz, Neutral.....	39
Table 27: Equipment List.....	41
Table 28: Equipment List.....	42
Table 29: Testing Software.....	42
Table 30: 9 kHz – 30 MHz Spurious Emissions on X-Axis.....	69
Table 31: 9 kHz – 30 MHz Spurious Emissions on Y-Axis.....	70
Table 32: 9 kHz – 30 MHz Spurious Emissions on Z-Axis.....	71
Table 33: 30 – 200 MHz Spurious Emissions	72
Table 34: AC Conducted Emission limits.....	77
Table 35: Conducted Emission – 13.56 MHz, Line.....	78
Table 36: Conducted Emissions – 13.56 MHz, Neutral.....	80

1 Executive Summary

1.1 Scope

This report is intended to document the status of conformance with the requirements of the *CFR Title 47 Subchapter A §Part 15.225 ISSED RSS-210 Issue 10*, based on the results of testing performed on 6/4/2024 to 6/11/2024 on EUT manufactured by Tokenize, Inc. This report only applies to the specific samples tested under the stated test conditions. It is the responsibility of the manufacturer to assure that additional production units of this model are manufactured with identical or EMI equivalent electrical and mechanical components. This report is further intended to document changes and modifications to the EUT throughout its life cycle. All documentation will be included as a supplement.

1.2 Purpose

Testing was performed to evaluate the EMC performance of the EUT with the integration of a certified radio module in accordance with the applicable requirements, procedures, and criteria defined in the application of regulations and application of standards listed in this report.

13.56 MHz RFID radio was examined in this report.

1.3 Summary of Test Results

Table 1: Summary of Test Results

Test	Regulatory Rule	Result
Unique Antenna Connector	47 CFR §15.203	Complied
Occupied Bandwidth	47 CFR §2.1049 RSS-Gen Section 6.7	Complied
Fundamental Field Strength	47 CFR §15.225(a) RSS-210 Annex B.6	Complied
Carrier Frequency Stability	47 CFR §2.1055 47 CFR §15.225(e) RSS-210 Annex B.6 RSS-Gen Section 6.11	Complied
Radiated Spurious Emissions	47 CFR §2.1053 47 CFR §15.225 (b), (c), (d) RSS-Gen Section 7.3 RSS-210 Annex B.6	Complied
AC Power Conducted Emissions	47 CFR §15.207 RSS-Gen Section 7.2	N/A ¹
Note: 1. AC Power Conducted Emissions was not performed due to the manufacturer not providing an AC Power Supply with the EUT.		

1.4 Special Accessories

None

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 9 of 81
Seite 9 von 81

1.5 Equipment Modifications

None

2 Laboratory Information

2.1 Accreditations & Endorsements

2.1.1 US Federal Communications Commission, US1131



TUV Rheinland of North America EMC test facilities located at 1279 Quarry Lane, Ste. A, Pleasanton, CA, 94566, and 5015 Brandin Ct, Fremont, CA. 94538, are recognized by the Commission for performing testing services for the general public on a fee basis. These laboratory test facilities have been fully described in reports submitted to and accepted by the FCC (Pleasanton Registration No. US1131, Fremont Registration No. US1131). The laboratory Scopes of Accreditation include Title 47 CFR Parts 15, 18 and 90. The accreditations are updated every three years.

2.1.2 NIST / A2LA, Testing Cert #3331.02



TUV Rheinland of North America EMC test facilities are accredited by the American Association for Laboratory Accreditation (A2LA). The laboratories have been assessed and accredited by A2LA in accordance with ISO Standard 17025:2017 (Testing Certificate #3331.02). The Scope of Laboratory Accreditation includes emission and immunity testing. The accreditations are updated annually.

2.1.3 Canada – Innovation, Science and Economic Development (ISED), 2932D



The Pleasanton 5-meter Semi-Anechoic Chamber, Registration No. 2932M-1, has been accepted by Industry Canada to perform testing to 3 and 5 meters based on the test procedures described in ANSI C63.4-2014. The Fremont 10-meter Semi-Anechoic Chamber, Registration No. 2932D-1, has been accepted by Industry Canada to perform testing to 3 and 10 meters based on the test procedures described in ANSI C63.4-2014

2.1.4 Japan – VCCI



The Voluntary Control Council for Interference by Information Technology Equipment (VCCI) is a group that consists of Information Technology Equipment (ITE) manufacturers and EMC test laboratories. The purpose of the Council is to take voluntary control measures against electromagnetic interference from Information Technology Equipment, and thereby contribute to the development of a socially beneficial and responsible state of affairs in the realm of Information Technology Equipment in Japan. TUV Rheinland of North America EMC test facilities located at 1279 Quarry Lane, Ste. A, Pleasanton, CA, 94566, and 5051 Brandin Ct, Fremont, CA. 94538, have been assessed and approved in accordance with the Regulations for Voluntary Control Measures.

VCCI Registration No. for Fremont: A-409

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 10 of 81
Seite 10 von 81

2.1.5 Acceptance by Mutual Recognition Arrangement



The United States has an established agreement with specific countries under the Asia Pacific Laboratory Accreditation Corporation (APLAC) Mutual Recognition Arrangement. Under this agreement, all TÜV Rheinland at 1279 Quarry Ln, Pleasanton, CA 94566 test results and test reports within the scope of the laboratory NIST / A2LA accreditation will be accepted by each member

country.

2.2 Test Facilities

Test facilities are located at 5015 Brandin Ct, Fremont, California, 94538, USA and 1279 Quarry Lane, Pleasanton, California 94566, USA (Fremont is the Pleasanton Annex).

2.2.1 Emission Test Facility

The Semi-Anechoic Chambers and AC Line Conducted measurement facilities used to collect radiated and conducted emissions data have been constructed in accordance with ANSI C63.7:1992. The Fremont 10 meter semi-anechoic chamber has been measured in accordance with and verified to comply with the theoretical volumetric normalized site attenuation of ANSI C63.4:2014 and SVSWR requirements of CISPR 16-1-4 Consol. Ed. 3.0 (2010-04), at test distances of 3 and 10 meters. This site has been described in reports dated November 1st, 2006, submitted to the FCC, and accepted by letter dated November 28, 2006. The site is listed with the FCC and accredited by A2LA (Testing Certificate #3331.02). The Pleasanton 5 meter semi-anechoic chamber has been verified to comply with the theoretical volumetric normalized site attenuation of ANSI C63.4:2009 and SVSWR requirements of CISPR 16-1-4 Consol. Ed. 3.0 (2010-04) at a test distance of 3 meters. This site has been described in reports dated November 1st, 2006, submitted to the FCC, and accepted by letter dated November 28, 2006. The site is listed with the FCC and accredited by A2LA (Testing Certificate #3331.02).

2.3 Measurement Uncertainty

Two types of measurement uncertainty are expressed in this report, per *ISO Guide To The Expression Of Uncertainty In Measurement*, 1st Edition, 1995.

The Combined Standard Uncertainty is the standard uncertainty of the result of a measurement when that result is obtained from the values of a number of other quantities; it is equal to the positive square root of the sum of the variances or co-variances of these other quantities, weighted according to how the measurement result varies with changes in these quantities. The term *standard uncertainty* is the result of a measurement expressed as a standard deviation.

The Expanded Uncertainty defines an interval about the result of a measurement that may be expected to encompass a large fraction of the distribution of values that could reasonably be attributed to the measurement and the fraction may be viewed as the coverage probability or level of confidence of the interval.

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 11 of 81
Seite 11 von 81

2.3.1 Sample Calculation – radiated & conducted emissions

The field strength is calculated by subtracting the Amplifier Gain and adding the Cable Loss and Antenna Correction Factor to the measured reading. The basic equation is as follows:

$$\text{Field Strength (dB}\mu\text{V/m)} = \text{RAW} - \text{AMP} + \text{CBL} + \text{ACF}$$

Where: RAW = Measured level before correction (dBμV)

AMP = Amplifier Gain (dB)

CBL = Cable Loss (dB)

ACF = Antenna Correction Factor (dB/m)

$$\mu\text{V/m} = 10^{\frac{\text{dB}\mu\text{V/m}}{20}}$$

Sample radiated emissions calculation @ 30 MHz

Measurement + Antenna Factor – Amplifier Gain + Cable loss = Radiated Emissions (dBuV/m)

$$25 \text{ dBuV/m} + 17.5 \text{ dB} - 20 \text{ dB} + 1.0 \text{ dB} = 23.5 \text{ dBuV/m}$$

2.3.2 Measurement Uncertainty

Per CISPR 16-4-2	U _{lab}	U _{cispr}
Radiated Disturbance @ 10 meters		
30 – 1,000 MHz	2.25 dB	4.51 dB
Radiated Disturbance @ 3 meters		
30 – 1,000 MHz	2.26 dB	4.52 dB
1 – 6 GHz	2.12 dB	4.25 dB
6 – 18 GHz	2.47 dB	4.93 dB
Conducted Disturbance @ Mains Terminals		
150 kHz – 30 MHz	1.09 dB	2.18 dB
Disturbance Power		
30 MHz – 300 MHz	1.09 dB	2.18 dB

Voltech PM6000A

The estimated combined standard uncertainty for harmonic current and flicker measurements is ± 5.0%.	Per CISPR 16-4-2 Methods
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Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 12 of 81
Seite 12 von 81

2.3.3 Measurement Uncertainty Immunity

The estimated combined standard uncertainty for ESD immunity measurements is $\pm 8.2\%$.	Per IEC 61000-4-2
The estimated combined standard uncertainty for radiated immunity measurements is ± 4.10 dB.	Per IEC 61000-4-3
The estimated combined standard uncertainty for conducted immunity measurements with CDN is ± 3.66 dB	Per IEC 61000-4-6
The estimated combined standard uncertainty for power frequency magnetic field immunity is $\pm 2.9\%$.	Per IEC 61000-4-8

Thermo KeyTek EMC Pro

The estimated combined standard uncertainty for EFT fast transient immunity measurements is $\pm 2.6\%$.
The estimated combined standard uncertainty for surge immunity measurements is $\pm 2.6\%$.
The estimated combined standard uncertainty for voltage variation and interruption measurements is $\pm 1.74\%$.

Measurement Uncertainty – Radio Testing

The estimated combined standard uncertainty for frequency error measurements is ± 3.88 Hz
The estimated combined standard uncertainty for carrier power measurements is ± 0.70 dB.
The estimated combined standard uncertainty for adjacent channel power measurements is ± 1.47 dB.
The estimated combined standard uncertainty for modulation frequency response measurements is ± 0.46 dB.
The estimated combined standard uncertainty for transmitter conducted emission measurements is ± 2.06 dB

The expanded uncertainty at a level of 95% confidence is obtained by multiplying the combined standard uncertainty by a coverage factor of 2. Compliance criteria are not based on measurement uncertainty.

2.4 Calibration Traceability

All measurement instrumentation is traceable to the National Institute of Standards and Technology (NIST). Measurement method complies with ANSI/NCSL Z540-1-1994 and ISO Standard 17025:2017. Equipment calibration records are kept on file at the test facility.

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 13 of 81
Seite 13 von 81

3 EMC Test Plan

3.1 Introduction

Section 3 provides a description of the Equipment Under Test (EUT), configurations, operating conditions, and performance acceptance criteria. It is an overview of information provided by the manufacturer (information supplied can affect validity of the results) so that the test laboratory may perform the requested testing.

3.2 Customer

Table 2: Customer Information

Client	Tokenize, Inc.
Address	4545 East River Road W. Henrietta, NY 14586
Contact Person	Timothy Harrington
Telephone	585-214-9587
Fax	Timothy.Harrington@tokenring.com

Table 3: Technical Contact Information

Contact Person	Timothy Harrington
Telephone	585-214-9587
E-Mail	Timothy.Harrington@tokenring.com

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 14 of 81
Seite 14 von 81

3.3 Equipment Under Test (EUT)

Table 4: EUT Specifications

EUT Specifications	
Dimensions	30mm x 30mm x 15mm
Power Input	5V
Operating Temperature Range:	15 to 120 F -9 to 49 C
Multiple Feeds:	☐ Yes and how many ☒ No
Hardware Version/Model	TokenRing V3, Token Biostick
Firmware Version	TR3: 0.9, TBK: 1.2.3
RF Software Version	1.16.0.0
Product Marketing Name	TR3, TBK
Operating Mode	Near Field Communication (Card Emulation - Passive)
Transmitter Frequency Band	13.56 MHZ (NFC)
Antenna Manufacturer	Tokenize, Inc.
Antenna Type	NFC: PCB Trace Antenna (loop)
Antenna Gain	0 dBi
Modulation Type	ASK
Data Rate	--
Supported Bandwidths	--
TX/RX Chain (s)	1
Directional Gain Type	☐ Uncorrelated ☐ Beam-Forming ☒ Other describe: N/A
Type of Equipment	☒ Table Top ☐ Wall-mount ☐ Floor standing cabinet ☐ Other: Indoor/Residential
Note: 1. All EUT specifications provided by manufacturer or TUV direct customer. 2. Information supplied by the customer and can affect the validity of the results.	

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 15 of 81
Seite 15 von 81

Table 5: EUT Test Samples

Equipment	Manufacturer	Model	Serial	Used for
Token Ring	Tokenize	TR3	240802ZD2406	Radiated Testing
Dev Board	Tokenize	TR3	240701ZD0024	Conducted Testing
Token Biostick	Tokenize	TBK	K02BA15C000 88	Additional Radiated Testing ¹
Note: 1. See Appendix 10 for additional spot check testing.				

Table 6: Channerl Power Setttng/Specifcation

Freq. (MHz)	--	--	--	--	--	--	--	--
Note: 1. Power is set by Manufacturer.								

Table 7: General Product Infomation

Dimensions	Length:	30 mm	Width:	30 mm	Height:	15 mm
Weight	--		Fork-lift Needed:		No	
Note: None						

Table 8: Electrical Power Type

Name	Type	Voltage		Frequency (Hz)	Current (A)
		Min	Max		
TokenRing V3	DC	5V	5V	--	--
Token Biostick	DC	5V	5V	--	--
Note: None					

Table 9: EUT Interface/Port Specifications

EUT Port	Connect To	Location	Length	Shielded/ Unshielded
N/A	--	--	--	--

4 Product Information

4.1 Product Description

Token Ring 3rd Generation and Token Biostick.

4.2 Equipment Configuration

A description of the equipment configuration is given in the Test Plan Section. The EUT was tested as called for in the test standard and was configured and operated in a manner consistent with its intended use. The placement of the EUT system components was guided by the test standard and selected to represent typical installation conditions.

In the case of an EUT that can operate in more than one configuration, preliminary testing was performed to determine the configuration that produced maximum radiation.

The final configuration was selected to produce the worst-case radiation for emissions testing.

4.3 Operating Mode

A description of the operation mode is given in the Test Plan Section. In the case of an EUT that can operate in more than one state, preliminary testing was performed to determine the operating mode that produced maximum radiation.

4.4 Unique Antenna Connector

An intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section. The manufacturer may design the unit so that a broken antenna can be replaced by the user, but the use of a standard antenna jack or electrical connector is prohibited. This requirement does not apply to carrier current devices or to devices operated under the provisions of §§ 15.211, 15.213, 15.217, 15.219, 15.221, or § 15.236. Further, this requirement does not apply to intentional radiators that must be professionally installed, such as perimeter protection systems and some field disturbance sensors, or to other intentional radiators which, in accordance with § 15.31(d), must be measured at the installation site. However, the installer shall be responsible for ensuring that the proper antenna is employed so that the limits in this part are not exceeded.

4.4.1 Results

The product utilizes a PCB Trace Antenna, and the end user has no access to the antenna.

5 Measurement Results

Testing was performed in accordance with CFR Title 47 Subchapter A §Part 15.225 & ISSED RSS-2010 Issue 10. These test methods are listed under the laboratory's A2LA Scope of Accreditation. This test measures the levels emanating from the EUT, thus evaluating the potential for the EUT to cause radio frequency interference to other electronic devices. Procedures described in section 5 of ANSI C63.10:2013 were employed.

Emission measurements below 30 MHz were performed at a 3-meter distance. The following is the correction factor that was applied to emissions which were subject to limits beyond 3 meters.

Correction factor, ΔFS , calculation (3 meter to 30 meter):

Equation (1) ANSI C63.10:2013 Section 6.4.4.1

$$d_{\text{near field}} = 47.77/f_{\text{MHz}}$$

Equation (2) ANSI C63.10:2013 Section 6.4.4.1

$$FS_{\text{limit}} - FS_{\text{max}} = -40 \log(d_{\text{near field}}/d_{\text{measure}}) - 20 \log(d_{\text{limit}}/d_{\text{near field}})$$

Where:

FS_{limit} $\equiv$ Field strength of the emission at the distance defined by regulator (calculated value).

FS_{max} $\equiv$ Measured field strength of the emission of interest (measured value).

$d_{\text{near field}}$ $\equiv$ the $\lambda/2\pi$ distance (3.52m).

d_{measure} $\equiv$ measurement distance (3m).

d_{limit} $\equiv$ reference limit distance (30m).

$FS_{\text{limit}} - FS_{\text{max}} \equiv \Delta FS$, correction factor to be applied to measured value in dB

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 18 of 81
Seite 18 von 81

5.1 Duty Cycle

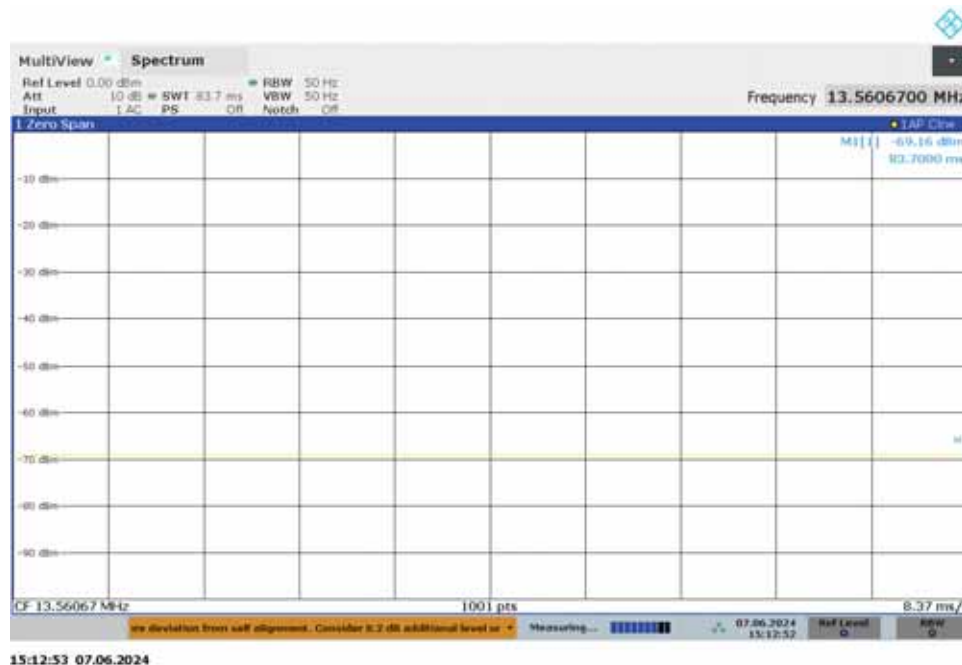
The duty cycle of the device was determined before testing was performed in order to choose the appropriate test methodology. Duty cycle was measured with a spectrum analyzer in zero span and calculated as the percentage between the transmitters on time over the signal period.

$$\text{Duty cycle \%} = (\text{Transmitter on time} / \text{Signal Period}) * 100$$

5.2 Results

Table 10: Duty Cycle

Test Condition:	Radiated, Normal Temperature	Date:	06/07/2024
Antenna Type:	PCB Trace Antenna (loop)	Power Level:	See Table 6
Ambient Temperature:	24°C	Relative Humidity:	38%
Max. Antenna Gain:	0 dBi	Test Engineer	Nathaniel Beyer
Signal State: Modulated			
ASK			
Frequency (MHz)	On-Time (ms)	Signal Period (ms)	Duty Cycle (%)
13.56	--	--	100
Note: N/A			



Duty Cycle

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 19 of 81
Seite 19 von 81

5.3 Fundamental Field Strength

The field strength of any emissions shall not exceed the following limits:

- 15,848 $\mu\text{V/m}$ (84 dB $\mu\text{V/m}$) at 30 m, within the band 13.553-13.567 MHz;
- 334 $\mu\text{V/m}$ (50.5 dB $\mu\text{V/m}$) at 30 m, within the bands 13.410-13.553 MHz and 13.567-13.710 MHz;
- 106 $\mu\text{V/m}$ (40.5 dB $\mu\text{V/m}$) at 30 m, within the bands 13.110-13.410 MHz and 13.710-14.010 MHz.

5.3.1 Test Methodology

The testing performed according to ANSI C63.10:2013 section 6.4. The measurements made were at 3-meter distance and the correction factor in section 5 was calculate and applied to the applicable emissions in this section.

5.3.2 Results

As originally tested the EUT was found to be compliant with the applicable requirements.

Table 11: Fundamental Field Strength

Test Condition:	Radiated, Normal Temperature					Date:	6/07/2024		
Antenna Type:	PCB Trace Antenna (loop)					Power Level:	See Table 6		
Ambient Temperature:	24 °C					Relative Humidity:	37 %		
Max. Antenna Gain:	0 dBi					Test Engineer	Nathaniel Beyer		
Signal State: Pulsed									
Freq. (MHz)	Quasi-Peak (dBμV/m)	ΔFS (dB)	Corrected Field Strength (dBμV/m)	Limit (dBμV/m)	Margin (dB)	BW (kHz)	Height (cm)	Pol	Azimuth (deg)
13.56	47.85	-21.39	26.46	84	57.54	100	100	X	317
13.56	47.81	-21.39	26.42	84	57.58	100	100	Y	240
13.56	62.06	-21.39	40.67	84	43.33	100	100	Z	186
Note:									
1. Measurement system losses have been put into the measurement reported (10.9 dB)									
2. Final Corrected value: Quasi-Peak + Duty Cycle correction + ΔFS									
3. Trace data can be found in section 5.4									

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 20 of 81
Seite 20 von 81

5.4 Occupied Bandwidth

The occupied bandwidth is the bandwidth in which 99% of the transmitted power is present.

5.4.1 Test Methodology

The testing was performed according to ANSI C63.10:2013 section 6.9.3.

5.4.2 Results

Table 12: Fundamental Field Strength

Test Condition:	Radiated, Normal Temperature	Date:	6/07/2024
Antenna Type:	PCB Trace Antenna (loop)	Power Level:	See Table 6
Ambient Temperature:	24°C	Relative Humidity:	38%
Max. Antenna Gain:	0 dBi	Test Engineer	Nathaniel Beyer
Signal State: Pulsed			
Frequency (MHz)		99% Occupied Bandwidth (Hz)	
13.56		1.52	
Note: None			



99% Occupied Bandwidth

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 21 of 81
Seite 21 von 81

5.5 Carrier Frequency Stability

Carrier frequency stability is a measure of the amount of drift the center of the transmit signal is from the nominal center frequency. The frequency stability is typically assessed in part per million (ppm) or percent (%).

5.5.1 Test Methodology

Testing was performed according to ANSI C63.10:2013 section 6.8. Temperature range assessed form -20 °C to +50 °C with a nominal supply voltage. The supply voltage is set from 85% to 115% of the nominal supply voltage at 20 °C.

5.5.2 Results

Table 13: Frequency Stability Over Temp (%)

Voltage	Temperature	Nominal Frequency	Frequency Stability (Hz)				Limit (%)
	°C	(MHz)	0min	2min	5min	10min	
Nominal (208 V)	50	13.56	13560656	13560656	13560656	13560657	± 0.01
	40	13.56	13560658	13560657	13560657	13560656	
	30	13.56	13560668	13560667	13560667	13560667	
	20	13.56	13560685	13560685	13560687	13560685	
	10	13.56	13560701	13560702	13560702	13560705	
	0	13.56	13560726	13560726	13560727	13560728	
	-10	13.56	13560737	13560737	13560738	13560738	
	-20	13.56	13560730	13560730	13560729	13560729	
Note: None							

Table 14: Frequency Stability Over Temp (PPM)

Voltage	Temperature	Nominal Frequency	Frequency Stability				Limit (PPM)
	°C	(MHz)	0min	2min	5min	10min	
Nominal (208 V)	50	13.56	48.4	48.4	48.4	48.5	± 100
	40	13.56	48.5	48.5	48.5	48.4	
	30	13.56	49.3	49.2	49.2	49.2	
	20	13.56	50.5	50.5	50.7	50.5	
	10	13.56	51.7	51.8	51.8	52.0	
	0	13.56	53.5	53.5	53.6	53.7	
	-10	13.56	54.4	54.4	54.4	54.4	
	-20	13.56	53.8	53.8	53.8	53.8	
Note: None							

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 22 of 81
Seite 22 von 81

Table 15: Frequency Stability Over Voltage (%)

Voltage	Temperature	Nominal Frequency	Frequency Stability (Hz)				Limit
Volts	°C	(MHz)	0min	2min	5min	10min	%
85% Vo	Ambient	13.56	13560681	13560681	13560680	13560679	± 0.01%
115% Vo	Ambient	13.56	13560682	13560684	13560681	13560681	
Note:							
1. Vo = 208 V							

Table 16: Frequency Stability Over Voltage (PPM)

Voltage	Temperature	Nominal Frequency	Frequency Stability				Limit
Volts	°C	(MHz)	0min	2min	5min	10min	%
85% Vo	Ambient	13.56	50.2	50.2	50.1	50.1	± 0.01%
115% Vo	Ambient	13.56	50.3	50.4	50.2	50.2	
Note: 1. Vo = 208 V							

5.6 Radiated Spurious Emissions

The field strength of any emissions shall not exceed the following limits:

15.848 $\mu\text{V/m}$ (84 dB $\mu\text{V/m}$) at 30 m, within the band 13.553-13.567 MHz;

334 $\mu\text{V/m}$ (50.5 dB $\mu\text{V/m}$) at 30 m, within the bands 13.410-13.553 MHz and 13.567-13.710 MHz;

106 $\mu\text{V/m}$ (40.5 dB $\mu\text{V/m}$) at 30 m, within the bands 13.110-13.410 MHz and 13.710-14.010 MHz

The field strength of any emissions appearing outside of the 13.110–14.010 MHz band shall not exceed the general radiated emission limits in § 15.209 or RSS-Gen Section 7.3.

5.6.1 Test Methodology

5.6.1.1 Preliminary Test

A test program that controls instrumentation and data logging was used to automate the preliminary RF emission test procedure. The frequency range of interest was divided into sub-ranges to yield a frequency resolution of approximately 120 kHz and provide a reading at each frequency for no more than 12° of turntable rotation. For each frequency sub-range the turntable was rotated 360° while peak emission data was recorded and plotted over the frequency range of interest in horizontal and vertical antenna polarization's.

Preliminary emission profile testing was performed inside the anechoic chamber. The EUT was placed on a 1.0m x 1.5m non-conductive table 80cm (<1 GHz) and 150cm (>1 GHz) above the floor. The EUT was positioned as shown in the setup photographs. The receiving antenna was placed at a distance of 3m at a fixed height of 1m. Measurement equipment was located outside of the chamber. A video camera was placed inside the chamber to view the EUT.

Pre-scans were performed to determine the worst data rate/chain.

5.6.1.2 Final Test

For each frequency measured, the peak emission was maximized by manipulating the receiving antenna from 1 to 4 meters above the ground plane and placing it at the position that produced the maximum signal strength reading. The turntable was then rotated through 360° while observing the peak signal and placing the EUT at the position that produced maximum radiation. The six highest emissions relative to the limit were measured unless such emissions were more than 20 dB below the limit. If less than six emissions are within 20 dB of the limit, then the noise level of the receiver is measured at frequencies where emissions are expected. Multiples of all oscillator and microprocessor frequencies were also checked.

Final testing was performed on an NSA compliant test site. The EUT was placed on a 1.0m x 1.5m non-conductive table 80cm (<1 GHz) and 150cm (>1 GHz) above the ground plane. The placement of EUT and cables were the same as for preliminary testing and is shown in the setup photographs.

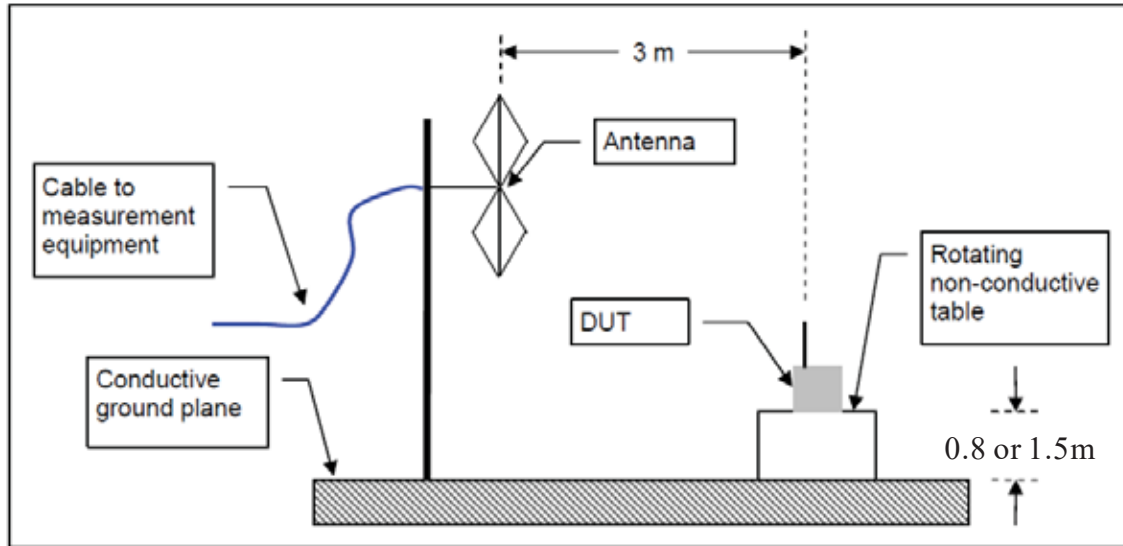
Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 24 of 81
Seite 24 von 81

5.6.1.3 Deviations

None.

5.6.1.4 Test Setup:



5.6.2 Transmitter Spurious Emission Limit

The spurious emissions of the transmitter shall not exceed the limits required by the applicable rule parts as described in section 5.5 and below.

Frequency (MHz)	Field Strength (microvolts/meter)	Measurement Distance (Meters)
0.009 – 0.490	2400/F(kHz)	300
0.490 – 1.705	24000/F(kHz)	30
1.705 – 30.0	30	30
30.0 – 88	100	3
88 – 216	150	3
216 – 960	200	3
Above 960	500	3

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 25 of 81
Seite 25 von 81

5.6.3 Test Results

The final measurement data was taken under the worst-case operating modes, configurations, and/or cable positions. It also reflects the results including any modifications and/or special accessories listed in Sections 1.4 and test plan. As originally tested, the EUT was found to be compliant to the requirements of the test standard(s).

5.6.4 Emission Mask

Table 17: Emissions Mask – X-Axis

Test Condition:		Radiated, Normal Temperature				Date:		06/07/2024		
Antenna Type:		PCB Trace Antenna (loop)				Power Level:		See Table 6		
Ambient Temperature:		24 °C				Relative Humidity:		37 %		
Max. Antenna Gain:		0 dBi				Test Engineer		Nathaniel Beyer		
Signal State: Pulsed										
Freq. (MHz)	Quasi-Peak (dBμV/m)	Peak (dBμV/m)	Limit (dBμV/m)	Margin (dB)	Meas. Time (ms)	BW (kHz)	Height (cm)	Pol	Azimuth (deg)	Corr. (dB)
13.12	-7.76	---	40.51	48.27	1000	9	155	X	47	10.9
13.29	-7.85	---	40.51	48.36	1000	9	155	X	40	10.9
13.39	-7.91	---	40.51	48.42	1000	9	155	X	302	10.9
13.50	-7.17	---	50.47	57.64	1000	9	155	X	343	10.9
13.56	27.87	---	84	56.13	1000	9	155	X	317	10.9
13.62	-6.84	---	50.47	57.31	1000	9	155	X	346	10.9
13.92	-8.09	---	40.51	48.6	1000	9	155	X	326	10.9
13.98	-7.97	---	40.51	48.48	1000	9	155	X	47	10.9
14.06	-8.19	---	40.51	48.7	1000	9	155	X	269	10.9
Note: 1. ΔFS correction has been added to the fundamental emissions (-21.39 dB) 2. Measurement system losses have been put into the measurement reported (Corr.) 3. Final Corrected value: Quasi-Peak + Duty Cycle correction + ΔFS + Corr										

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 26 of 81
Seite 26 von 81

Table 18: Emissions Mask – Y-Axis

Test Condition:		Radiated, Normal Temperature				Date:		06/07/2024		
Antenna Type:		PCB Trace Antenna (loop)				Power Level:		See Table 6		
Ambient Temperature:		24 °C				Relative Humidity:		37 %		
Max. Antenna Gain:		0 dBi				Test Engineer		Nathaniel Beyer		
Signal State: Pulsed										
Freq. (MHz)	Quasi-Peak (dBμV/m)	Peak (dBμV/m)	Limit (dBμV/m)	Margin (dB)	Meas. Time (ms)	BW (kHz)	Height (cm)	Pol	Azimuth (deg)	Corr. (dB)
12.95	-7.66	---	40.51	48.17	1000	9	155	Y	180	10.9
13.03	-7.65	---	40.51	48.16	1000	9	155	Y	249	10.9
13.21	-7.94	---	40.51	48.45	1000	9	155	Y	76	10.9
13.32	-7.81	---	50.47	58.28	1000	9	155	Y	107	10.9
13.40	-7.89	---	84	91.89	1000	9	155	Y	147	10.9
13.56	24.81	---	50.47	25.66	1000	9	155	Y	240	10.9
13.71	-7.78	---	40.51	48.29	1000	9	155	Y	228	10.9
13.81	-7.82	---	40.51	48.33	1000	9	155	Y	123	10.9
14.06	-8.21	---	40.51	48.72	1000	9	155	Y	332	10.9
Note:										
1. ΔFS correction has been added to the fundamental emissions (-21.39 dB)										
2. Measurement system losses have been put into the measurement reported (Corr.)										
3. Final Corrected value: Quasi-Peak + Duty Cycle correction + ΔFS + Corr										

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 27 of 81
Seite 27 von 81

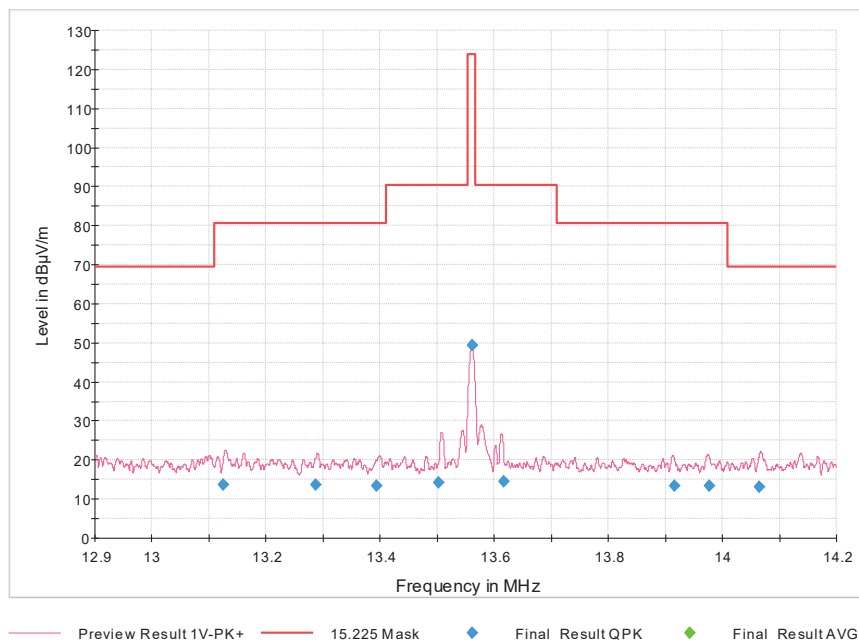
Table 19: Emissions Mask – Z-Axis

Test Condition:		Radiated, Normal Temperature				Date:		06/07/2024		
Antenna Type:		PCB Trace Antenna (loop)				Power Level:		See Table 6		
Ambient Temperature:		24 °C				Relative Humidity:		38 %		
Max. Antenna Gain:		0 dBi				Test Engineer		Nathaniel Beyer		
Signal State: Pulsed										
Freq. (MHz)	Quasi-Peak (dBμV/m)	Peak (dBμV/m)	Limit (dBμV/m)	Margin (dB)	Meas. Time (ms)	BW (kHz)	Height (cm)	Pol	Azimuth (deg)	Corr. (dB)
13.00	-7.7	---	40.51	48.21	1000	9	155	Z	323	10.9
13.14	-6.2	---	40.51	46.71	1000	9	155	Z	323	10.9
13.28	-7.39	---	40.51	47.9	1000	9	155	Z	326	10.9
13.35	-0.14	---	40.51	40.65	1000	9	155	Z	323	10.9
13.42	-3.49	---	50.47	53.96	1000	9	155	Z	326	10.9
13.48	0.22	---	50.47	50.25	1000	9	155	Z	323	10.9
13.56	40.91	---	84	43.09	1000	9	155	Z	186	10.9
13.64	-0.59	---	50.47	51.06	1000	9	155	Z	326	10.9
13.69	-1.75	---	50.47	52.22	1000	9	155	Z	323	10.9
13.77	0.46	---	40.51	40.05	1000	9	155	Z	323	10.9
13.99	-5.3	---	40.51	45.81	1000	9	155	Z	323	10.9
14.07	-7.43	---	40.51	47.94	1000	9	155	Z	323	10.9
Note:										
1. ΔFS correction has been added to the fundamental emissions (-21.39 dB)										
2. Measurement system losses have been put into the measurement reported (Corr.)										
3. Final Corrected value: Quasi-Peak + Duty Cycle correction + ΔFS + Corr										

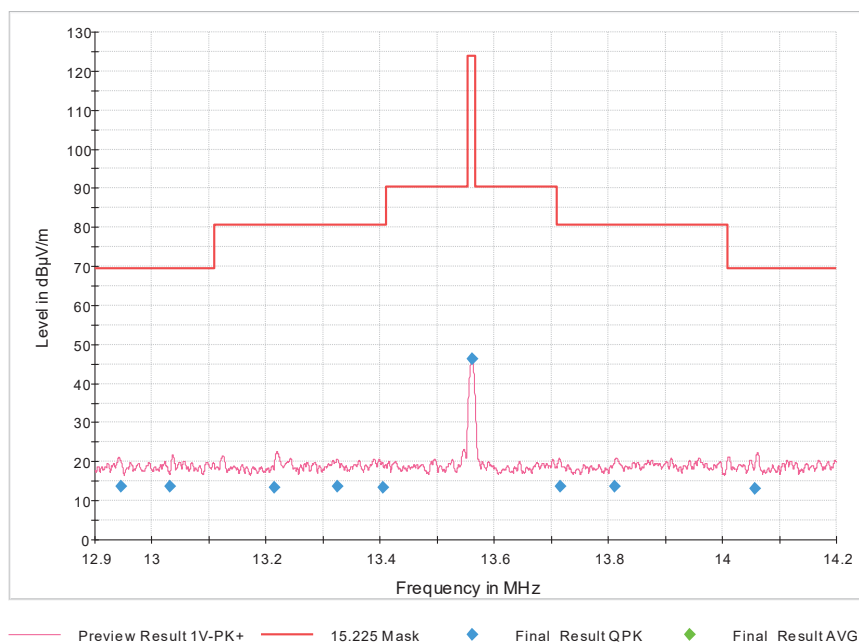
Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 28 of 81
Seite 28 von 81

5.6.4.1 Emission Mask Trace Data



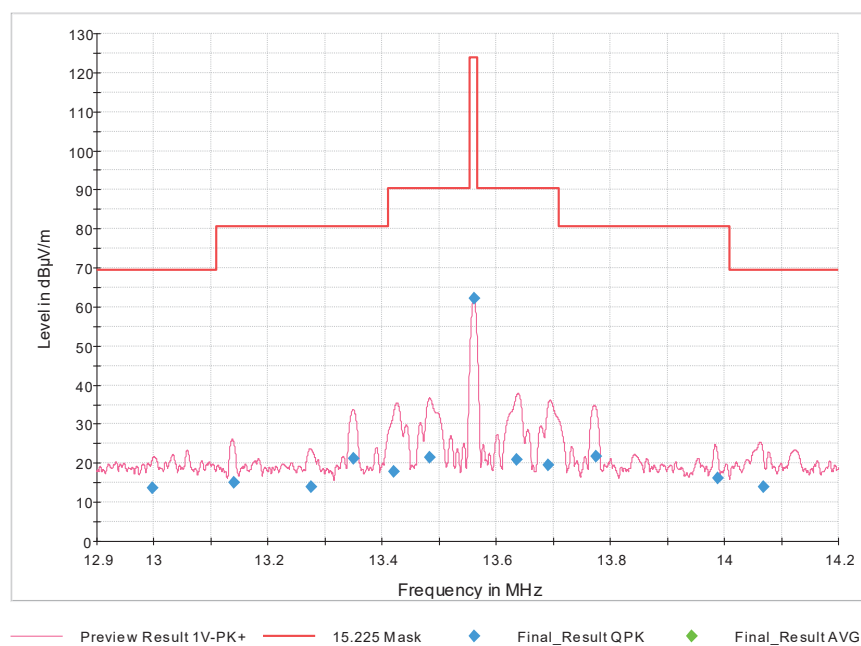
Emissions Mask – X-Axis



Emission Mask – Y-Axis

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 29 of 81
Seite 29 von 81



Emission Mask – Z-Axis

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 30 of 81
Seite 30 von 81

5.6.5 Spurious Emissions

Table 20: 9 kHz – 30 MHz Spurious Emissions on X-Axis

Test Condition:		Radiated, Normal Temperature				Date:		06/10/2024		
Antenna Type:		PCB Trace Antenna (loop)				Power Level:		See Table 6		
Ambient Temperature:		24 °C				Relative Humidity:		37 %		
Max. Antenna Gain:		0 dBi				Test Engineer		Nathaniel Beyer		
Signal State: Pulsed										
Freq. (MHz)	Quasi-Peak (dBµV/m)	Peak (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Meas. Time (ms)	BW (kHz)	Height (cm)	Pol (V/H)	Azimuth (deg)	Corr. (dB)
0.027	---	37.67	118.89	81.22	1000	0.2	155	Y	0	13.8
0.055	---	32.93	112.87	79.94	1000	0.2	155	Y	248	11.8
0.178	---	26.23	102.58	76.35	1000	9	155	Y	208	11.3
0.602	31.09	---	72.01	40.92	1000	9	155	Y	102	11.5
1.205	22.93	---	65.98	43.05	1000	9	155	Y	98	11.8
1.799	10.27	---	69.54	59.27	1000	9	155	Y	110	11.8
2.480	7.28	---	69.54	62.26	1000	9	155	Y	114	11.7
3.024	13.89	---	69.54	55.65	1000	9	155	Y	117	11.5
3.628	11.01	---	69.54	58.53	1000	9	155	Y	117	11.6
5.438	0.82	---	69.54	68.72	1000	9	155	Y	117	11.4
13.56	28.04	---	69.54	41.5	1000	9	155	Y	0	10.9
27.12	19.06	---	69.54	50.48	1000	9	155	Y	192	9.3
Note:										
1. The correction factor described in Section 5 has been applied to final measurement values.										

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 31 of 81
Seite 31 von 81

Table 21: 9 kHz – 30 MHz Spurious Emissions on Y-Axis

Test Condition:		Radiated, Normal Temperature				Date:		06/10/2024		
Antenna Type:		PCB Trace Antenna (loop)				Power Level:		See Table 6		
Ambient Temperature:		24 °C				Relative Humidity:		37 %		
Max. Antenna Gain:		0 dBi				Test Engineer		Nathaniel Beyer		
Signal State: Pulsed										
Freq. (MHz)	Quasi-Peak (dBµV/m)	Peak (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Meas. Time (ms)	BW (kHz)	Height (cm)	Pol (V/H)	Azimuth (deg)	Corr. (dB)
0.02	---	26.73	121.58	94.85	1000	0.2	155	Y	207	14.2
0.08	---	17.09	109.34	92.25	1000	0.2	155	Y	0	11.6
0.50	22.5	---	73.56	51.06	1000	9	155	Y	278	11.4
0.61	26.31	---	71.93	45.62	1000	9	155	Y	31	11.5
1.21	21.52	---	65.94	44.42	1000	9	155	Y	146	11.8
1.31	13.05	---	65.28	52.23	1000	9	155	Y	330	11.8
1.82	17.19	---	69.54	52.35	1000	9	155	Y	146	11.8
3.02	6.1	---	69.54	63.44	1000	9	155	Y	146	11.5
13.56	27.54	---	69.54	42	1000	9	155	Y	255	10.9
27.12	13.84	---	69.54	55.7	1000	9	155	Y	258	9.3
Note:										
1. The correction factor described in Section 5 has been applied to final measurement values.										

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 32 of 81
Seite 32 von 81

Table 22: 9 kHz – 30 MHz Spurious Emissions on Z-Axis

Test Condition:		Radiated, Normal Temperature				Date:		06/07/2024		
Antenna Type:		PCB Trace Antenna (loop)				Power Level:		See Table 6		
Ambient Temperature:		24 °C				Relative Humidity:		38 %		
Max. Antenna Gain:		0 dBi				Test Engineer		Nathaniel Beyer		
Signal State: Pulsed										
Freq. (MHz)	Quasi-Peak (dBµV/m)	Peak (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Meas. Time (ms)	BW (kHz)	Height (cm)	Pol (V/H)	Azimuth (deg)	Corr. (dB)
0.02	---	29.3	123.51	94.21	1000	0.2	155	Z	146	15.9
0.05	---	29.31	112.9	83.59	1000	0.2	155	Z	84	11.8
0.59	22.89	---	72.14	49.25	1000	9	155	Z	106	11.5
0.62	25.11	---	71.8	46.69	1000	9	155	Z	116	11.5
1.2	20.29	---	66.03	45.74	1000	9	155	Z	106	11.8
1.8	19.71	---	69.54	49.83	1000	9	155	Z	106	11.8
1.87	15.67	---	69.54	53.87	1000	9	155	Z	127	11.8
3.11	10.31	---	69.54	59.23	1000	9	155	Z	116	11.5
13.56	62.21	---	69.54	7.33	1000	9	155	Z	189	10.9
27.12	30.32	---	69.54	39.22	1000	9	155	Z	119	9.3
Note: The correction factor described in Section 5 has been applied to final measurement values.										

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 33 of 81
Seite 33 von 81

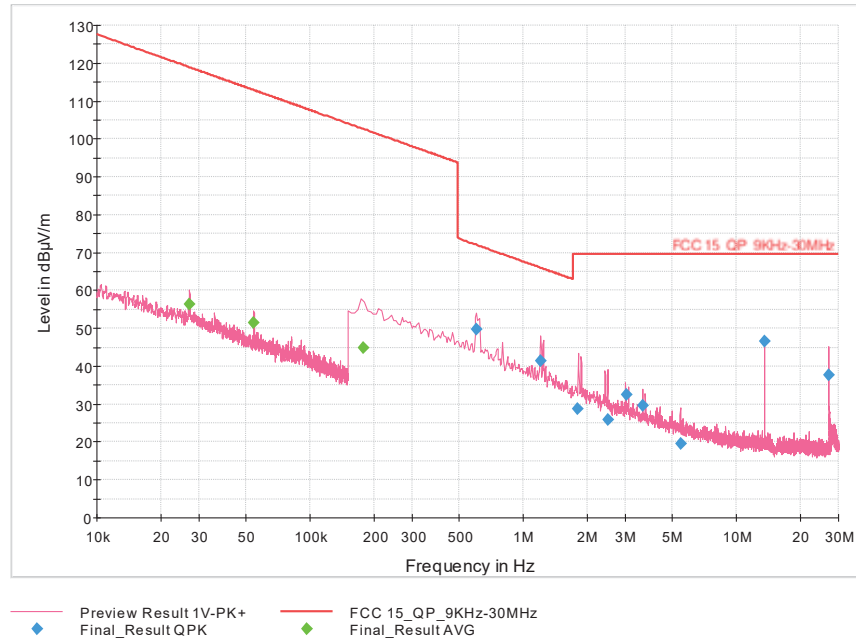
Table 23: 30 – 1000 MHz Spurious Emissions

Test Condition:		Radiated, Normal Temperature				Date:		06/10/2024		
Antenna Type:		PCB Trace Antenna (loop)				Power Level:		See Table 6		
Ambient Temperature:		24 °C				Relative Humidity:		35 %		
Max. Antenna Gain:		0 dBi				Test Engineer		Nathaniel Beyer		
Signal State: Pulsed										
Freq. (MHz)	Quasi-Peak (dBµV/m)	Peak (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Meas. Time (ms)	BW (kHz)	Height (cm)	Pol (V/H)	Azimuth (deg)	Corr (dB)
40.67	25.68	---	40	14.32	1000	120	100	V	281	-12.5
40.67	---	27.88	---	---	1000	120	100	V	281	-12.5
63.16	---	31.5	---	---	1000	120	354	H	150	-13.3
63.16	21.26	---	40	18.74	1000	120	354	H	150	-13.3
96.88	22.28	---	43.52	21.24	1000	120	105	V	89	-12.6
96.88	---	27.5	---	---	1000	120	105	V	89	-12.6
162.73	---	34.65	---	---	1000	120	100	V	273	-16.6
162.73	30.19	---	43.52	13.33	1000	120	100	V	273	-16.6
167.25	---	34.24	---	---	1000	120	100	V	99	-16.6
167.25	28.43	---	43.52	15.09	1000	120	100	V	99	-16.6
168.96	---	37.26	---	---	1000	120	100	V	127	-16.5
168.96	30.86	---	43.52	12.66	1000	120	100	V	127	-16.5
172.64	---	32.59	---	---	1000	120	100	V	127	-16.5
172.64	27.21	---	43.52	16.31	1000	120	100	V	127	-16.5
180.62	22.58	---	43.52	20.94	1000	120	100	V	127	-15.8
180.62	---	28.9	---	---	1000	120	100	V	127	-15.8
189.85	---	30.48	---	---	1000	120	176	H	53	-14.6
189.85	27.23	---	43.52	16.29	1000	120	176	H	53	-14.6
273.40	27.28	---	46	18.72	1000	120	100	H	96	-12.5
273.40	---	30.4	---	---	1000	120	100	H	96	-12.5
410.40	---	27.8	---	---	1000	120	100	H	9	-9.4
410.40	24.03	---	46	21.97	1000	120	100	H	9	-9.4
596.06	---	27.62	---	---	1000	120	195	V	14	-7
596.06	16.89	---	46	29.11	1000	120	195	V	14	-7
949.24	---	31.42	---	---	1000	120	100	H	31	-2.8
949.24	27.57	---	46	18.43	1000	120	100	H	31	-2.8
Note: None										

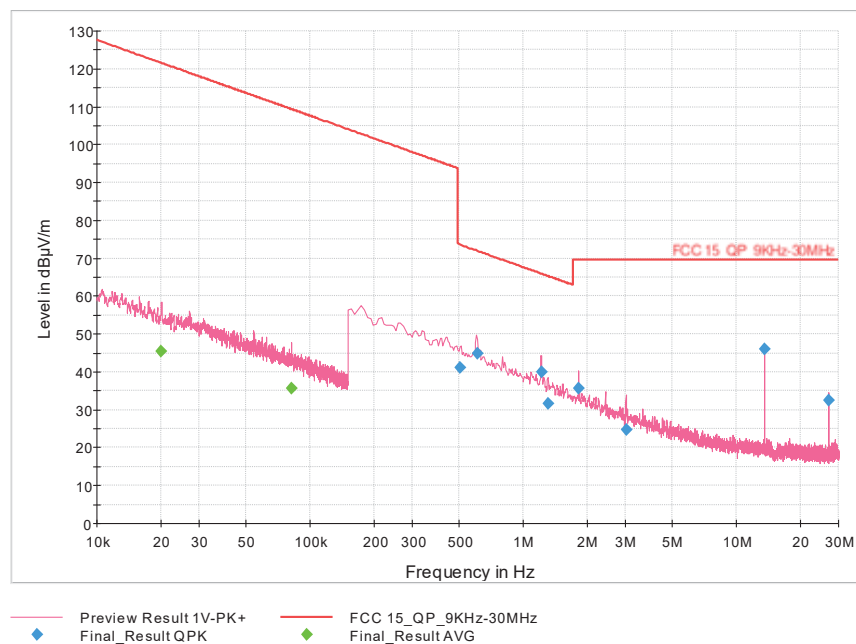
Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 34 of 81
Seite 34 von 81

5.6.5.1 Spurious Emission Trace Data



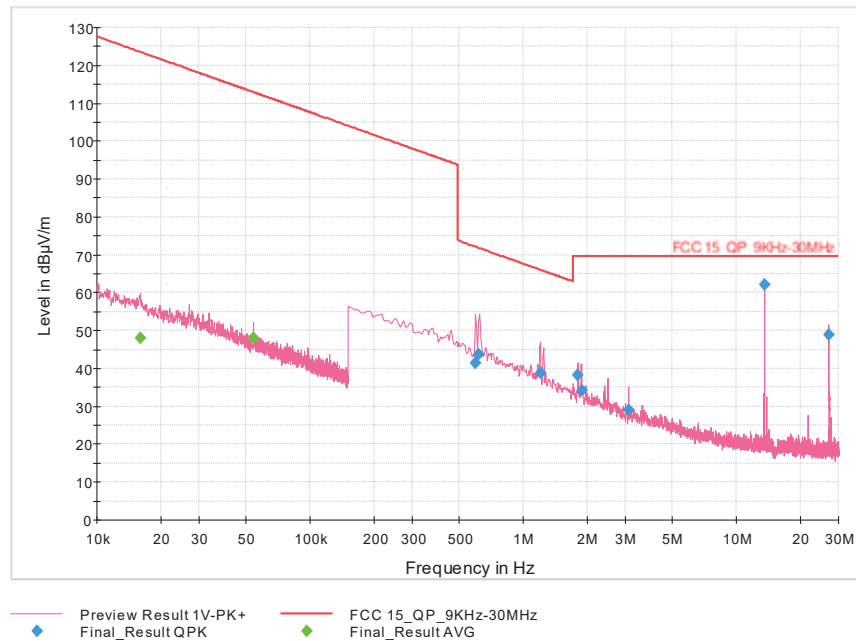
9 kHz to 30 MHz Radiated Emissions – X-Axis



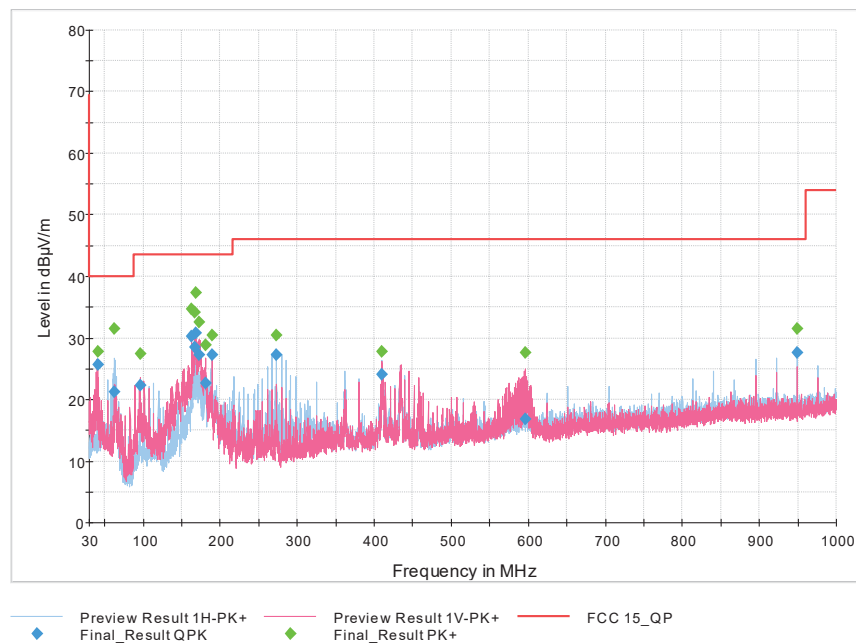
9 kHz to 30 MHz Radiated Emissions – Y-Axis

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 35 of 81
Seite 35 von 81



9 kHz to 30 MHz Radiated Emissions – Z-Axis



30 – 1000 MHz Radiated Emissions

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 36 of 81
Seite 36 von 81

5.7 AC Mains Conducted Emissions

Testing was performed in accordance with ANSI C63.4:2020. These test methods are listed under the laboratory's A2LA Scope of Accreditation.

This test measures the levels emanating from the EUT's AC input port, thus evaluating the potential for the EUT to cause radio frequency interference to other electronic devices.

The AC conducted emissions of equipment under test shall not exceed the values in CFR47 Part 15.207 and RSS-Gen Section 8.8.

5.7.1 Test Methodology

A test program that controls instrumentation and data logging was used to automate the AC Power Line Conducted emission test procedure. The frequency range of interest was divided into sub-ranges such as to yield a frequency resolution of 9 kHz. Each phase and neutral of the AC power line were measured with respect to ground. Measurements were performed using a set of 50 μ H / 50 Ω LISNs.

The setup photographs clearly identify which site was used. The vertical ground plane used is a 2m x 2m solid aluminum frame and panel, and it is bonded to the horizontal ground plane.

In the case of tabletop equipment, the EUT is placed on a 1.0m x 1.5m non-conductive table 80cm above the ground plane and 40cm from a vertical ground reference plane. The rear of the EUT was positioned flush with the backside of the table and directly over the LISNs. The power and I/O cables were routed over the edge of the table and bundled approximately 40cm from the ground plane. Support equipment was powered from a separate LISN.

The radio's were transmitting when testing was performed.

5.7.2 Conducted Emission Limits

The emissions of the EUT shall not exceed the limits required by the applicable rule parts as described below.

Table 24: AC Conducted Emission limits

Frequency of Emission (MHz)	Conducted Limit (dB μ V)	
	Quasi-Peak	Average
0.15 – 0.5	66 to 56 ¹	56 to 46 ¹
0.5 – 5	56	46
5 – 30	60	50
Note:		
1. Decreases with the logarithm of the frequency.		

5.7.3 Deviations

There were no deviations from this test methodology.

5.7.4 Test Results

The device passed as configured.

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 37 of 81
Seite 37 von 81

5.7.4.1 Test Data

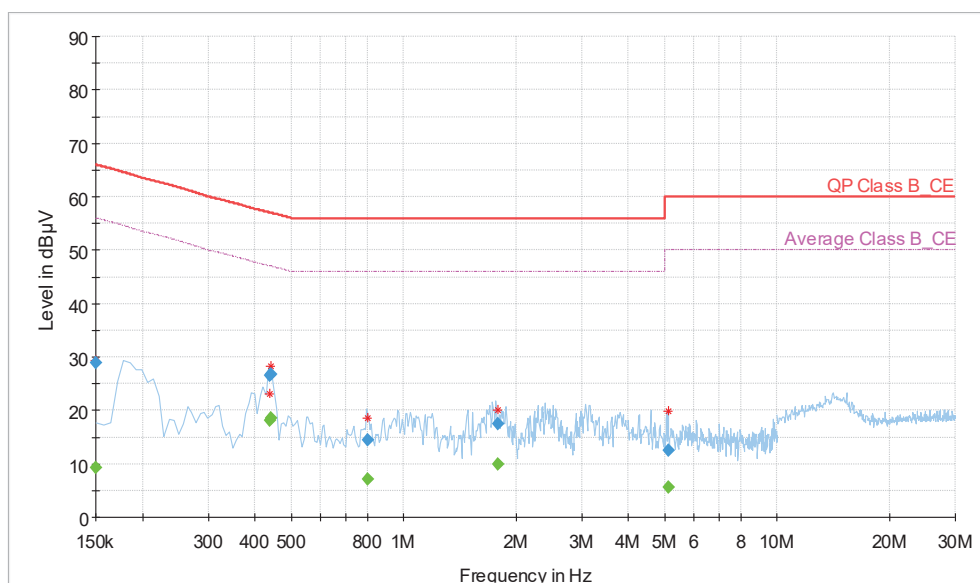
5.7.4.1.1 Conducted Emissions

Table 25: Conducted Emission – 13.56 MHz, Line

Test Condition:		Radiated, Normal Temperature			Date:	08/26/2025		
Antenna Type:		PCB Trace Antenna (loop)			Power Level:	See Table 6		
Ambient Temperature:		23°C			Relative Humidity:	40%		
Max. Antenna Gain:		0 dBi			Test Engineer	Nathaniel Beyer		
Signal State: Modulated								
Freq. (MHz)	Quasi-Peak (dBµV/m)	Average (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Meas. Time (ms)	Line	PE	Corr. (dB)
0.15	---	9.2	56	46.8	10000	L1	GND	10.1
0.15	28.95	---	66	37.05	10000	L1	GND	10.1
0.44	---	18.15	47.02	28.87	10000	L1	GND	10
0.44	26.51	---	57.02	30.51	10000	L1	GND	10
0.44	---	18.59	46.98	28.4	10000	L1	GND	10
0.44	26.73	---	56.98	30.26	10000	L1	GND	10
0.80	---	7.17	46	38.83	10000	L1	GND	10
0.80	14.43	---	56	41.57	10000	L1	GND	10
1.79	---	9.95	46	36.06	10000	L1	GND	10
1.79	17.54	---	56	38.46	10000	L1	GND	10
5.11	---	5.61	50	44.39	10000	L1	GND	10.1
5.11	12.52	---	60	47.48	10000	L1	GND	10.1
Note: None								

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 38 of 81
Seite 38 von 81



Preview Result 1-PK+
Average Class B_CE

* Critical_Freqs PK+
Final_Result QPK

QP Class B_CE
Final_Result AVG

Conducted Emissions: Line

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

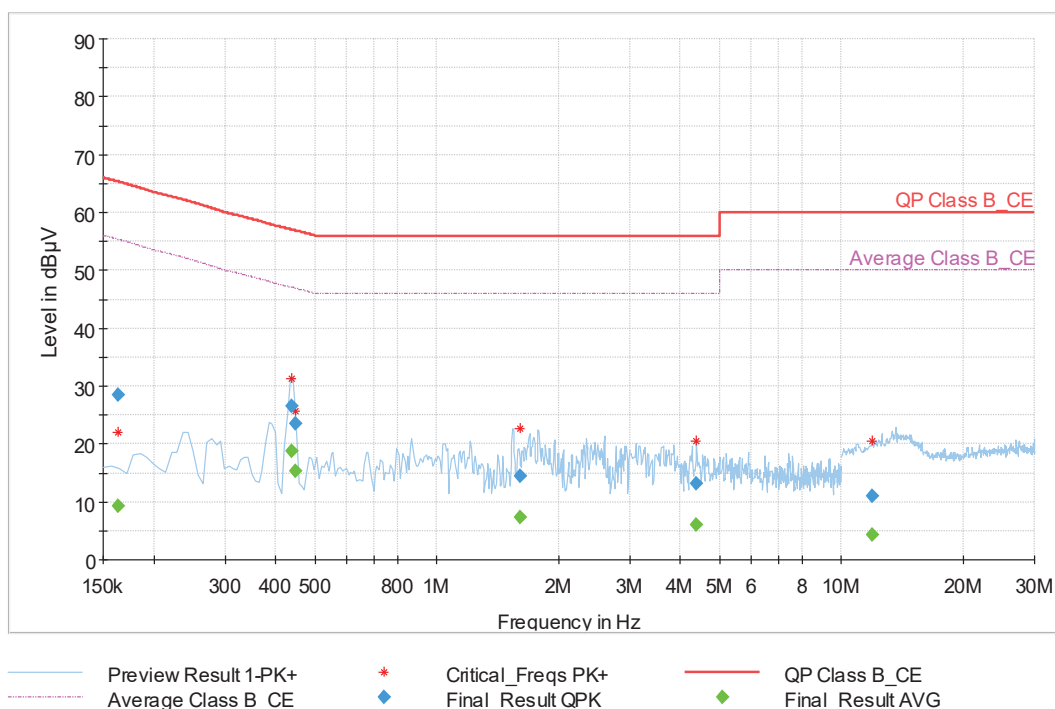
Page 39 of 81
Seite 39 von 81

Table 26: Conducted Emissions – 13.56 MHz, Neutral

Test Condition:		Radiated, Normal Temperature			Date:	08/26/2025		
Antenna Type:		PCB Trace Antenna (loop)			Power Level:	See Table 6		
Ambient Temperature:		23°C			Relative Humidity:	40%		
Max. Antenna Gain:		0 dBi			Test Engineer	Nathaniel Beyer		
Signal State: Modulated								
Freq. (MHz)	Quasi-Peak (dBµV/m)	Average (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Meas. Time (ms)	Line	PE	Corr. (dB)
0.16	---	9.29	55.33	46.03	10000	N	GND	10.1
0.16	28.4	---	65.33	36.92	10000	N	GND	10.1
0.44	26.46	---	57.04	30.58	10000	N	GND	10
0.44	---	18.76	47.04	28.27	10000	N	GND	10
0.45	23.44	---	56.87	33.43	10000	N	GND	10
0.45	---	15.42	46.87	31.45	10000	N	GND	10
1.61	---	7.33	46	38.67	10000	N	GND	10
1.61	14.56	---	56	41.44	10000	N	GND	10
4.37	---	6.1	46	39.9	10000	N	GND	10.1
4.37	13.2	---	56	42.8	10000	N	GND	10.1
11.89	---	4.33	50	45.67	10000	N	GND	10.1
11.89	11.01	---	60	48.99	10000	N	GND	10.1
Note: None								

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 40 of 81
Seite 40 von 81



Conducted Emissions: Neutral

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 41 of 81
Seite 41 von 81

6 Test Equipment List

6.1 Equipment List

Table 27: Equipment List

Equipment	Type	Inventory Number	Manufacturer	Last calibration	Calibration due date
Radiated Emissions					
EMI Test Receiver	ESW44	9018108	Rohde & Schwarz	21.02.2024	21.02.2025
Preamplifier 30MHz – 8 GHz	TS-PR8	9017639	Rohde & Schwarz	22.02.2024	22.02.2025
Preamplifier 1GHz – 18GHz	TS-PR18	9018047	Rohde & Schwarz	27.02.2024	27.02.2025
Horn Antenna 1GHz – 18GHz	3115	9038283	EMCO	14.09.2023	14.09.2025
Trilog Antenna 30MHz – 7GHz	VULB 9162	9017943	Schwarzbeck; Huber+ Suhner	24.03.2023	24.03.2025
Loop Antenna 10 kHz – 30 MHz	6502	G1700997	EMCO	23.05.2024	23.05.2026
Conducted RF					
EMI Test Receiver	ESW44	90229914	Rohde & Schwarz	20.02.2024	20.02.2025
DC Power Supp DC Power Supply ly	E36104B	9066184	Keysight	--	--
Temperature Chamber	BTZ-133	G1700388	ESPEC	--	--
Thermometer	52II	G1703473	Fluke	23.02.2024	23.02.2025
Conducted Emissions					
EMI Test Receiver	ESW44	9022991	Rohde & Schwarz	02.04.2025	02.04.2026
LISN	LI-215	G1700229	Com-Power	18.02.2025	18.02.2026
Transient Limiter	11947A	G1701026	Agilent	18.02.2025	18.02.2026
Note: Initial testing on TR3 from 6/4/2024 - 6/11/2024 & 8/26/2025					

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 42 of 81
Seite 42 von 81

Table 28: Equipment List

Equipment	Type	Inventory Number	Manufacturer	Last calibration	Calibration due date
Radiated Emissions					
EMI Test Receiver	ESW44	9018108	Rohde & Schwarz	21.02.2024	21.02.2025
Preamplifier 30MHz – 8 GHz	TS-PR8	9017639	Rohde & Schwarz	22.02.2024	22.02.2025
Trilog Antenna 30MHz – 7GHz	VULB 9162	9017943	Schwarzbeck; Huber+ Suhner	24.03.2023	24.03.2025
Loop Antenna 10 kHz – 30 MHz	6502	G1700997	EMCO	23.05.2024	23.05.2026
Conducted Emissions					
EMI Test Receiver	ESW44	9022991	Rohde & Schwarz	02.04.2025	02.04.2026
LISN	LI-215	G1700229	Com-Power	18.02.2025	18.02.2026
Transient Limiter	11947A	G1701026	Agilent	18.02.2025	18.02.2026
Note: Additional testing on TBK on 8/15/2025 – 08/26/2025					

6.2 Testing Software

Table 29: Testing Software

Manufacturer	Name	Version	Test
Rohde & Schwarz	EMC32	3m – 10.60.10	Radiated Emissions
Rohde & Schwarz	EMC32	CE - 10.50.10	Conducted Emissions

Test report no.: US24AI4K 001
Prüfbericht-Nr.:

Page 43 of 81
Seite 43 von 81

--- Ende des Prüfberichts / *End of Test Report* ---